



Rev. A, October 2008

FQH44N10_F133

100V N-Channel MOSFET

General Description

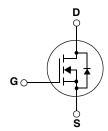
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

Features

- 48A, 100V, $R_{DS(on)} = 0.039\Omega$ @ $V_{GS} = 10 V$
- Low gate charge (typical 48 nC)
- Low Crss (typical 85 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · 175°C maximum junction temperature rating





Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQH44N10_F133	Units	
V_{DSS}	Drain-Source Voltage		100	V	
I _D	Drain Current - Continuous (T _C = 25°C)	48	Α	
	- Continuous (T _C = 100°C)		34	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	192	Α	
V_{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	530	mJ	
I _{AR}	Avalanche Current	(Note 1)	48	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	18	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		180	W	
	- Derate above 25°C		1.2	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C	
TL	Maximum lead temperature for soldering purposes, 1/8∀ from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.83	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

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Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C			0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V				1	μА
		V _{DS} = 80 V, T _C = 150°C				10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	aracteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 24 A			0.03	0.039	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 24 A	(Note 4)		31		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		 	1400 425 85	1800 550 110	pF pF pF
C _{rss}	Reverse Transfer Capacitance				85	110	pF
Switchi	ing Characteristics					ı	ı
t _{d(on)}	Turn-On Delay Time	V _{DD} = 50 V, I _D = 43.5 A,		19	45	ns	
t _r	Turn-On Rise Time	$R_G = 25 \Omega$ (Note 4, 5)			190	390	ns
t _{d(off)}	Turn-Off Delay Time				90	190	ns
t _f	Turn-Off Fall Time				100	210	ns
Qg	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 43.5 \text{ A},$ $V_{GS} = 10 \text{ V}$			48	62	nC
Q _{gs}	Gate-Source Charge				9.0		nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		24		nC
Drain-S	Source Diode Characteristics a	nd Maximum Rating	5				
I _S	Maximum Continuous Drain-Source Did					48	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				192	Α	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 48 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 43.5 \text{ A},$			98		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs	(Note 4)		360		nC

- 2. L = 0.345mH, I_{AS} = 48A, V_{DD} = 25V, R_{G} = 25 Ω , Starting T_{J} = 25°C 3. I_{SD} \leq 43.5A, di/dt \leq 300A/ μ s, V_{DD} \leq BV $_{DSS}$, Starting T_{J} = 25°C 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

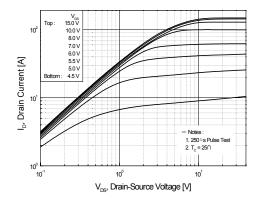


Figure 1. On-Region Characteristics

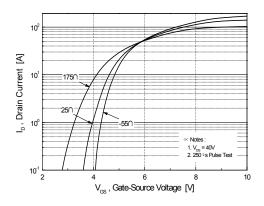


Figure 2. Transfer Characteristics

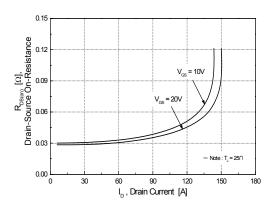


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

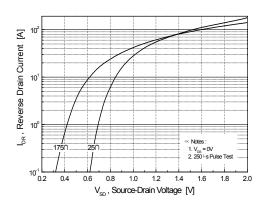


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

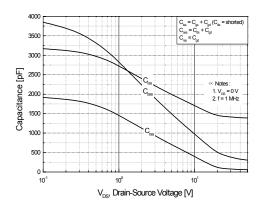


Figure 5. Capacitance Characteristics

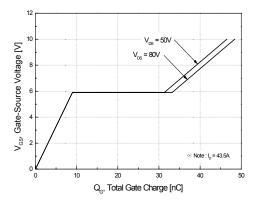
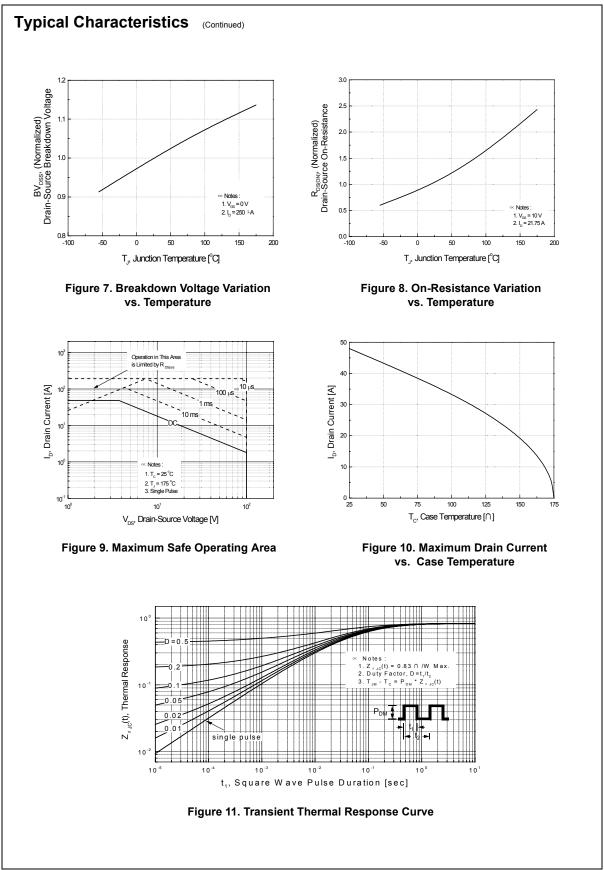
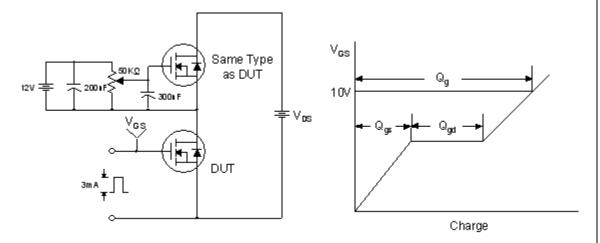


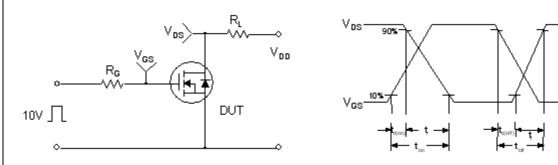
Figure 6. Gate Charge Characteristics



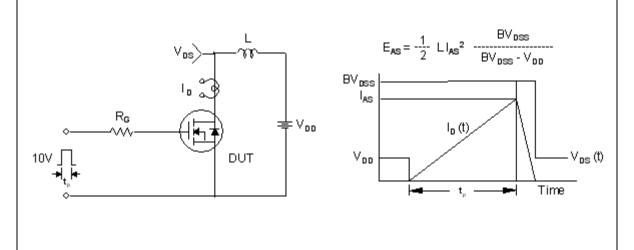
Gate Charge Test Circuit & Waveform



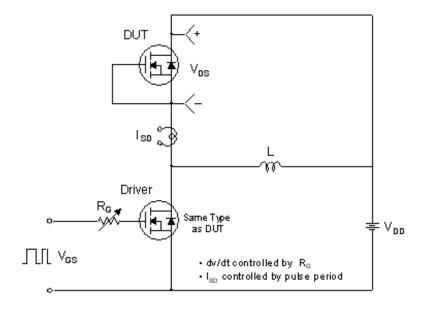
Resistive Switching Test Circuit & Waveforms

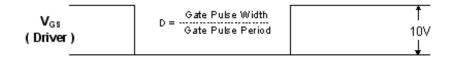


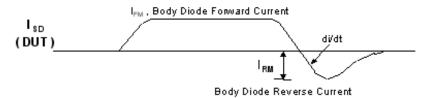
Unclamped Inductive Switching Test Circuit & Waveforms

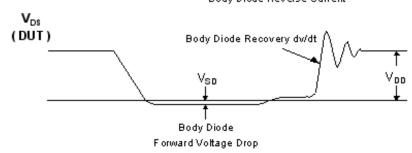


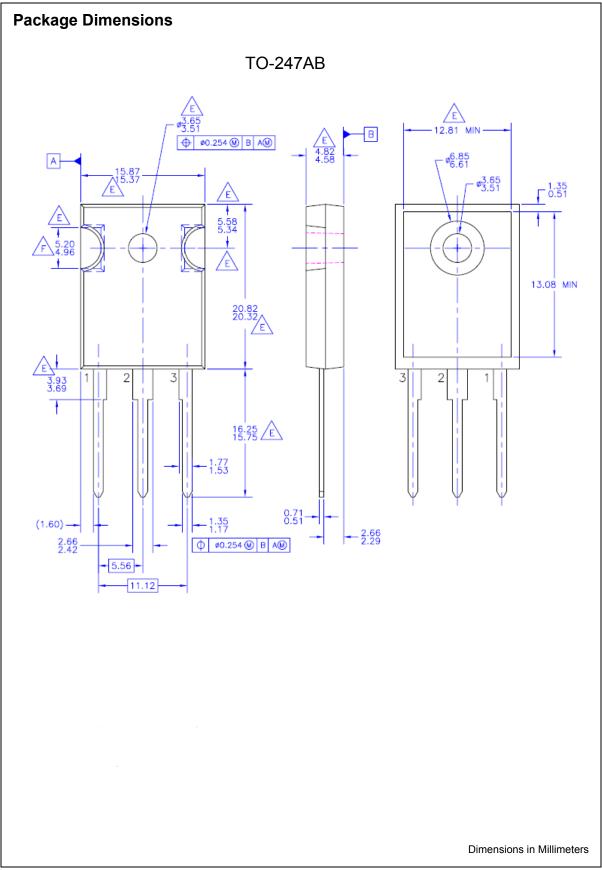
Peak Diode Recovery dv/dt Test Circuit & Waveforms















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